

INTERNATIONAL SEARCH REPORT

Int. Application No
PCT/IL2004/000915

A. CLASSIFICATION OF SUBJECT MATTER

IPC 7 H01L27/06 H01L27/148 H01L31/02

According to International Patent Classification (IPC) or to both national classification and IPC

B. FIELDS SEARCHED

Minimum documentation searched (classification system followed by classification symbols)

IPC 7 H01L

Documentation searched other than minimum documentation to the extent that such documents are included in the fields searched

Electronic data base consulted during the international search (name of data base and, where practical, search terms used)

EPO-Internal, INSPEC

C. DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
X	TEWKSBUURY S K ET AL: "Cointegration of optoelectronics and submicron CMOS" WAFER SCALE INTEGRATION, 1993. PROCEEDINGS., FIFTH ANNUAL IEEE INTERNATIONAL CONFERENCE ON SAN FRANCISCO, CA, USA 20-22 JAN. 1993, NEW YORK, NY, USA, IEEE, US, 20 January 1993 (1993-01-20), pages 358-367, XP010067696 ISBN: 0-7803-0867-0	1,8,11
Y	page 362, line 1 - page 366, line 50; figures 5-9	3,4,6,7, 10,12,14
Y	US 6 416 218 B1 (CHEUNG LIM) 9 July 2002 (2002-07-09) column 1, line 60 - column 3, line 13; figures 2-6 column 5, line 58 - column 8, line 20	3,6,7, 10,12,14
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☒ Further documents are listed in the continuation of box C.

☒ Patent family members are listed in annex.

* Special categories of cited documents :

- *A* document defining the general state of the art which is not considered to be of particular relevance
- *E* earlier document but published on or after the international filing date
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- *O* document referring to an oral disclosure, use, exhibition or other means
- *P* document published prior to the international filing date but later than the priority date claimed

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- *X* document of particular relevance; the claimed invention cannot be considered novel or cannot be considered to involve an inventive step when the document is taken alone
- *Y* document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document is combined with one or more other such documents, such combination being obvious to a person skilled in the art.
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Date of the actual completion of the international search

27 January 2005

Date of mailing of the international search report

04/02/2005

Name and mailing address of the ISA

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C.(Continuation) DOCUMENTS CONSIDERED TO BE RELEVANT

Category *	Citation of document, with indication, where appropriate, of the relevant passages	Relevant to claim No.
A	FLACK W W ET AL: "Lithographic manufacturing techniques for wafer scale integration" WAFER SCALE INTEGRATION, 1992. PROCEEDINGS., Y4TH INTERNATIONAL CONFERENCE ON SAN FRANCISCO, CA, USA 22-24 JAN. 1992, LOS ALAMITOS, CA, USA, IEEE COMPUT. SOC, US, 22 January 1992 (1992-01-22), pages 4-13, XP010026528 ISBN: 0-8186-2482-5 the whole document	1-12
P, A	WO 03/083944 A1 (INTERON AS; NYGARD, EINAR; BUTNARO, SHARONA) 9 October 2003 (2003-10-09) the whole document	1-12
Y	WO 02/067014 A1 (REAL-TIME RADIOGRAPHY LTD; HAREL, ZE'EV; SCHIEBER, MICHAEL; SAADO, YEH) 29 August 2002 (2002-08-29)	4
A	page 14, line 1 - page 16, line 12; figures 1,2	1

INTERNATIONAL SEARCH REPORT

Information on patent family members

International Application No
PCT/IL2004/000915

Patent document cited in search report	Publication date	Patent family member(s)	Publication date
US 6416218	B1	US 6005911 A	21-12-1999
WO 03083944	A1	EP 1483790 A1	08-12-2004
WO 02067014	A1	NONE	